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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the application of

George et al

Serial No: 10/803,453

Filed: March 18, 2004

For: SLOTTED ELECTROSTATIC SHIELD
MODIFICATION FOR IMPROVED ETCH AND CVD
PROCESS UNIFORMITY

Examiner: Luz L Alejandro Mulero

Art Unit: 1763

Attorney Docket: MAT-8

Date: June 1, 2005

CERTIFICATE OF MAILING I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail in an envelope addressed to: Commissioner of Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on June 1, 2005.

Signed:

Jay R Beyer

Commissioner of Patents
P.O. Box 1450
Alexandria, VA 22313-1450

CERTIFICATION PURSUANT TO 37 C.F.R. §1.97(e)

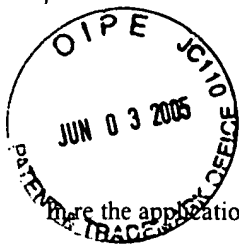
Sir:

I hereby certify that each item of information contained in this Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application not more than 3 months prior to the filing date of this statement as evidenced by the enclosed copy of the Notification of Transmittal of the International Search Report for the PCT application associated with the subject application.

Respectfully submitted,

Jay R Beyer

Registration No. 39,907



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Jay R Beyer

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P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

Enclosed is a copy of Information Disclosure Citation Form PTO-1449. It is respectfully requested that the cited documents be considered and that the enclosed copy of Information Disclosure Citation Form PTO-1449 be initialed by the Examiner to indicate such consideration and a copy thereof returned to applicant(s).

Pursuant to 37 C.F.R. § 1.97, the submission of this Information Disclosure Statement is not to be construed as a representation that a search has been made and is not to be construed as an admission that the information cited in this statement is material to patentability.

Pursuant to 37 C.F.R. § 1.97, this Information Disclosure Statement is being submitted under one of the following (as indicated by an "X" to the left of the appropriate paragraph):

 37 C.F.R. § 1.97(b).

 X 37 C.F.R. § 1.97(c). If so, then enclosed with this Information Disclosure Statement is one of the following:

 X A certification pursuant to 37 C.F.R. § 1.97(e) or

A check for \$ for the fee under 37 C.F.R. § 1.17(p).

 37 C.F.R. § 1.97(d). If so, then enclosed with this Information Disclosure Statement are the following:

(1) A certification pursuant to 37 C.F.R. § 1.97(e);

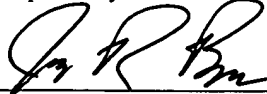
(2) A petition requesting consideration of the Information Disclosure Statement; and

(3) A check for \$ for the fee under 37 C.F.R. § 1.17(i) for submission of the

Information Disclosure Statement.

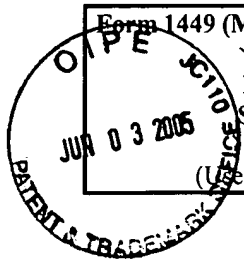
If there are any additional charges, please charge Deposit Account No. 19-1685 (Order No. MAT-8).

Respectfully submitted,



Jay R Beyer

Registration No. 39,907



Form 1449 (Modified)

Information Disclosure
Statement By Applicant

(Use Several Sheets if Necessary)

Atty Docket No.

MAT-8

Applicants:

George, et al

Filing Date

March 18, 2004

Serial No.:

10/803,453

Art Unit

1763

U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
	A	5,903,106 A	5/11/1999	Young et al			
	B	6,459,066 B1	10/1/2002	Khater et al.			
	C	2002/0185229 A1	12/12/2002	Brcka et al.			
	D						
	E						
	F						
	G						

Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	H							
	I							
	J							
	K							

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	L	
	M	
	N	
Examiner		Date Considered

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.